Application/Control No.	Applicant(s)/Patent under Reexamination	
10/578,309	BLANC ET AL.	
Examiner	Art Unit	
Y. J. Han	2838	

SEARCHED					
Class	Subclass	Date	Examiner		
363	40				
	41				
	56.02				
	71				
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	132				
307	82				
•	85				
	86	3/2/2007	JH		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
See sea	rch report	3/5/2007	JH	

•	DATE	EXMR
PLUS	3/2/2007	JH